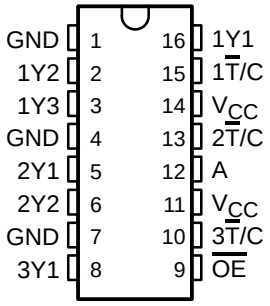
CDC392
1-LINE TO 6-LINE CLOCK DRIVER WITH SELECTABLE POLARITY AND 3-STATE OUTPUTS

SCAS335A – DECEMBER 1992 – REVISED NOVEMBER 1995

- **Low Output Skew for Clock-Distribution and Clock-Generation Applications**
- **TTL-Compatible Inputs and CMOS-Compatible Outputs**
- **Distributes One Clock Input to Six Clock Outputs**
- **Polarity Control Selects True or Complementary Outputs**
- **Distributed V_{CC} and GND Pins Reduce Switching Noise**
- **High-Drive Outputs (–32-mA I_{OH}, 32-mA I_{OL})**
- **State-of-the-Art *EPIC*-II*B*™ BiCMOS Design Significantly Reduces Power Dissipation**
- **Packaged In Plastic Small-Outline Package**

D PACKAGE
(TOP VIEW)



description

The CDC392 contains a clock-driver circuit that distributes one input signal to six outputs with minimum skew for clock distribution. Through the use of the polarity-control ($\overline{T}$/C) inputs, various combinations of true and complementary outputs can be obtained. The output-enable ($\overline{OE}$) input is provided to disable the outputs to a high-impedance state.

The CDC392 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE

INPUTS			OUTPUT
$\overline{OE}$	$\overline{T}$/C	A	Y
H	X	X	Z
L	L	L	L
L	L	H	H
L	H	L	H
L	H	H	L

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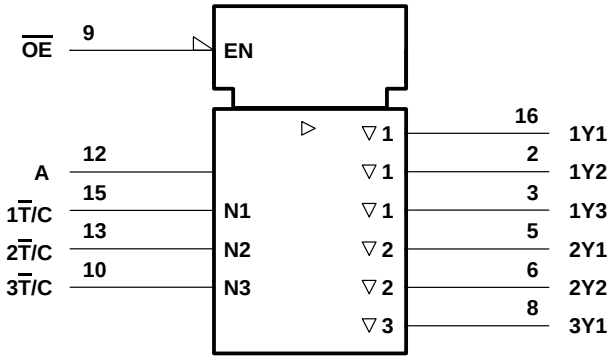
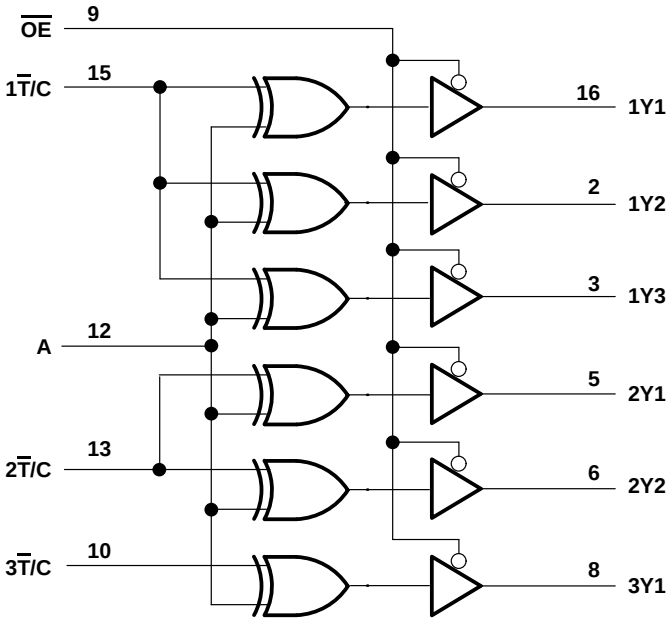
logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I (see Note 1) . . . . . –0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, V_O . . . . . –0.5 V to V_{CC} + 0.5 V
Current into any output in the low state, I_O . . . . . 64 mA
Input clamp current, I_{IK} (V_I < 0) . . . . . –18 mA
Output clamp current, I_{OK} (V_O < 0) . . . . . –50 mA
Maximum power dissipation at T_A = 55°C (in still air) (see Note 2) . . . . . 0.77 W

Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 300 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.

recommended operating conditions (see Note 3)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
V_I	Input voltage	0		V_{CC}	V
I_{OH}	High-level output current			–32	mA
I_{OL}	Low-level output current			32	mA
$\Delta t/\Delta v$	Input transition rise or fall rate			5	ns/V
f_{clock}	Input clock frequency			90	MHz
T_A	Operating free-air temperature	–40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

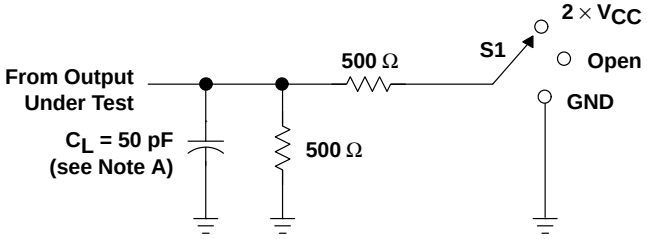
PARAMETER	TEST CONDITIONS			MIN	TYP†	MAX	UNIT
V_{IK}	V_{CC} = 4.75 V,	I_I = –18 mA				–1.2	V
V_{OH}	V_{CC} = 4.75 V,	I_{OH} = – 32 mA		3.85			V
V_{OL}	V_{CC} = 4.75 V,	I_{OL} = 32 mA				0.55	V
I_I	V_{CC} = 5.25 V,	V_I = V_{CC} or GND				±1	µA
I_{OZ}	V_{CC} = 5.25 V,	V_O = V_{CC} or GND				±50	µA
I_{CC}	V_{CC} = 5.25 V, V_I = V_{CC} or GND	I_O = 0,	Outputs high			10	mA
			Outputs low			40	
			Outputs disabled			10	
C_i	V_I = 2.5 V or 0.5 V				3		pF
C_o	V_O = V_{CC} or GND				7		pF

† All typical values are at V_{CC} = 5 V, T_A = 25°C

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

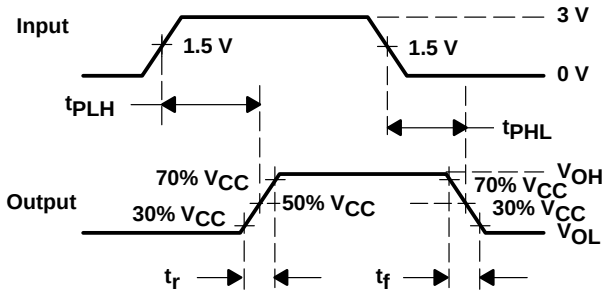
PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
t_{PLH}	A	Any Y	2		6.5	ns
t_{PHL}			1.5		5	
t_{PLH}	$\overline{T}$/C	Any Y	1.5		5	ns
t_{PHL}			1.5		5	
t_{PZH}	$\overline{OE}$	Any Y	1.5		6	ns
t_{PZL}			3		8	
t_{PHZ}	$\overline{OE}$	Any Y	1.5		5	ns
t_{PLZ}			1.5		5	
$t_{sk(o)}$	A	Any Y (same phase)			0.6	ns
		Any Y (any phase)			2.2	
t_r				1.4		ns
t_f				0.83		ns

PARAMETER MEASUREMENT INFORMATION

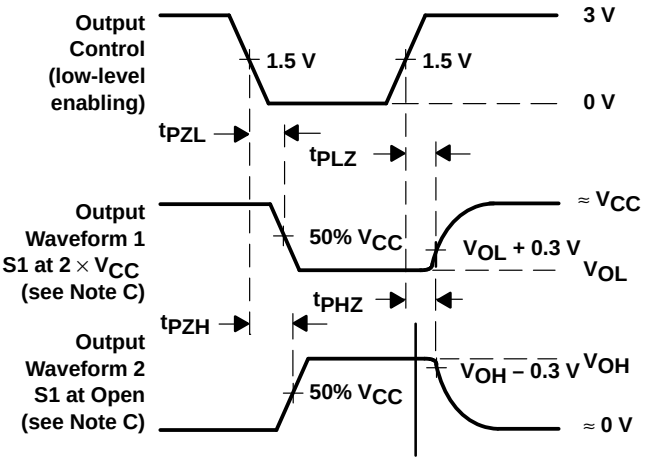


TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	Open

LOAD CIRCUIT FOR OUTPUTS



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

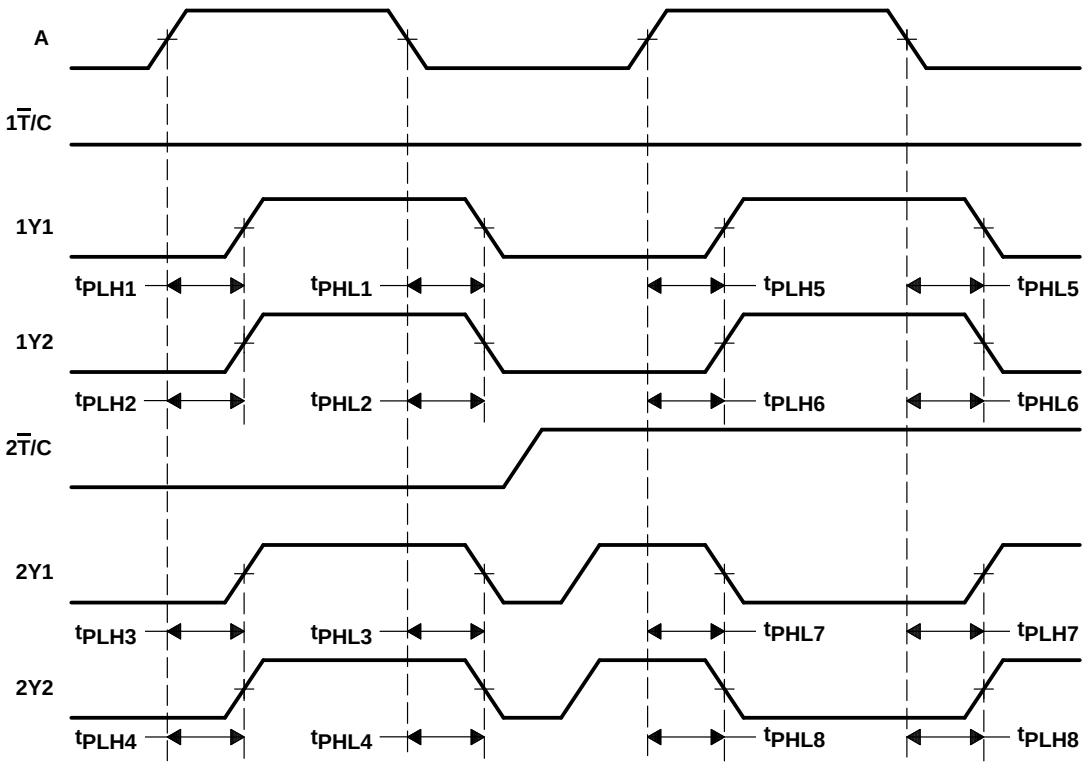


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION



NOTES: A. Output skew, $t_{sk(o)}$, from A to any Y (same phase), can be measured only between outputs for which the respective polarity-control inputs ($\overline{T}$/C) are at the same logic level. It is calculated as the greater of:
- The difference between the fastest and slowest of t_{PLH} from A↑ to any Y (e.g., t_{PLHn}, n = 1 to 4; or t_{PLHn}, n = 5 to 6)
- The difference between the fastest and slowest of t_{PHL} from A↓ to any Y (e.g., t_{PHLn}, n = 1 to 4; or t_{PHLn}, n = 5 to 6)
- The difference between the fastest and slowest of t_{PLH} from A↓ to any Y (e.g., t_{PLHn}, n = 7 to 8)
- The difference between the fastest and slowest of t_{PHL} from A↑ to any Y (e.g., t_{PHLn}, n = 7 to 8)

B. Output skew, $t_{sk(o)}$, from A to any Y (any phase), can be measured between outputs for which the respective polarity-control inputs ($\overline{T}$/C) are at the same or different logic levels. It is calculated as the greater of:
- The difference between the fastest and slowest of t_{PLH} from A↑ to any Y or t_{PHL} from A↑ to any Y (e.g., t_{PLHn}, n = 1 to 4; or t_{PLHn}, n = 5 to 6, and t_{PHLn}, n = 7 to 8)
- The difference between the fastest and slowest of t_{PHL} from A↓ to any Y or t_{PLH} from A↓ to any Y (e.g., t_{PHLn}, n = 1 to 4; or t_{PHLn}, n = 5 to 6, and t_{PLHn}, n = 7 to 8)

Figure 2. Waveforms for Calculation of $t_{sk(o)}$

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